Power MOSFET

30 V, 63 A, Single N-Channel, DPAK/IPAK

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- NVD Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable
- These are Pb-Free Devices

Applications

- CPU Power Delivery
- DC-DC Converters
- Low Side Switching

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Para	Parameter			Value	Unit
Drain-to-Source Vo	ltage		V_{DSS}	30	V
Gate-to-Source Vol	Gate-to-Source Voltage			±20	V
Continuous Drain Current R _{θJA}		T _A = 25°C	I _D	13.8	Α
(Note 1)		T _A = 85°C		10.7	
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P _D	2.63	W
Continuous Drain Current R _{0.IA}		T _A = 25°C	ID	10	Α
(Note 2)	Steady State	T _A = 85°C		7.8	
Power Dissipation $R_{\theta JA}$ (Note 2)	State	T _A = 25°C	P _D	1.4	W
Continuous Drain Current R _{θJC}]	T _C = 25°C	I _D	63	Α
(Note 1)		T _C = 85°C		49	
Power Dissipation R _{θJC} (Note 1)		T _C = 25°C	P _D	54.6	W
Pulsed Drain Current	t _p =10μs	T _A = 25°C	I _{DM}	126	Α
Current Limited by P	ackage	T _A = 25°C	I _{DmaxPkg}	45	Α
Operating Junction a Temperature	Operating Junction and Storage Temperature			–55 to +175	ç
Source Current (Body Diode)			IS	45	Α
Drain to Source dV/dt			dV/dt	6	V/ns
Single Pulse Drain–to–Source Avalanche Energy (V_{DD} = 24 V, V_{GS} = 10 V, I_L = 17 A_{pk} , L = 1.0 mH, R_G = 25 Ω)			EAS	144.5	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

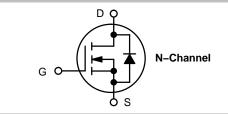
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
00.14	8.0 mΩ @ 10 V	
30 V	12.4 mΩ @ 4.5 V	63 A



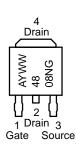


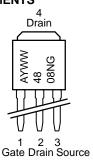


CASE 369AA STYLE 2

IPAK CASE 369D STYLE 2

MARKING DIAGRAMS & PIN ASSIGNMENTS





A = Assembly Location*

Y = Year WW = Work Week 4808N = Device Code G = Pb-Free Package

ORDERING INFORMATION

See detailed ordering and shipping information on page 6 of this data sheet.

^{*} The Assembly Location code (A) is front side optional. In cases where the Assembly Location is stamped in the package, the front side assembly code may be blank.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	2.75	
Junction-to-TAB (Drain)	$R_{ heta JC-TAB}$	3.5	°C/W
Junction-to-Ambient - Steady State (Note 1)	$R_{ heta JA}$	57	-C/VV
Junction-to-Ambient - Steady State (Note 2)	$R_{ heta JA}$	107	

- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.

ELECTRICAL CHARACTERISTICS (T₁ = 25°C unless otherwise specified)

Parameter	Symbol	Test Condit	tion	Min	Тур	Max	Unit
OFF CHARACTERISTICS	•				•		
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				27		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 24 V	$T_J = 25 ^{\circ}\text{C}$ $T_J = 125 ^{\circ}\text{C}$			1 10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS}$	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 3)					I.		
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$: 250 μΑ	1.5		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.6		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 to 11.5 V	I _D = 30 A		6.7	8.0	
			I _D = 15 A		6.6		mΩ
		V _{GS} = 4.5 V	I _D = 30 A		10.3	12.4	
			I _D = 15 A		9.8		
Forward Transconductance	9FS	V _{DS} = 15 V, I _D = 15 A			11.4		S
CHARGES AND CAPACITANCES							
Input Capacitance	C _{ISS}				1538		
Output Capacitance	C _{OSS}	$V_{GS} = 0 \text{ V, f} = 1 \text{ MHz}$	z, V _{DS} = 12 V		334		pF
Reverse Transfer Capacitance	C _{RSS}				180		
Total Gate Charge	$Q_{G(TOT)}$				11.3	13	
Threshold Gate Charge	Q _{G(TH)}	V 45VV 4	5 \		1.6]
Gate-to-Source Charge	Q _{GS}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			4.9		nC
Gate-to-Drain Charge	Q_{GD}				4.9		
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = 11.5 \text{ V}, V_{DS} = 15 \text{ V};$ $I_{D} = 30 \text{ A}$			26		nC
SWITCHING CHARACTERISTICS (Note	4)					_	
Turn-On Delay Time	t _{d(ON)}				12.3		
Rise Time	t _r	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}, I_{D} = 15 \text{ A},$ $R_{G} = 3.0 \Omega$			21.3]
Turn-Off Delay Time	t _{d(OFF)}				14.6		ns
	1						1

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
Switching characteristics are independent of operating junction temperatures.

6.0

Fall Time

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified) (continued)

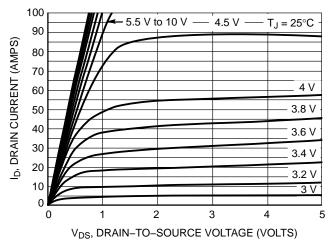
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	Note 4)			-			
Turn-On Delay Time	t _{d(ON)}	$V_{GS} = 11.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 15 \text{ A}, R_{G} = 3.0 \Omega$			7.7		
Rise Time	t _r				19.5		
Turn-Off Delay Time	t _{d(OFF)}	$I_D = 15 A, R_G$	= 3.0 Ω		23		ns
Fall Time	t _f				3.5		
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	V_{SD}	$V_{GS} = 0 V$	$T_J = 25^{\circ}C$		0.93	1.2	.,
		$V_{GS} = 0 \text{ V},$ $I_{S} = 30 \text{ A}$ $I_{J} = 25^{\circ}\text{C}$ $I_{J} = 125^{\circ}\text{C}$		0.83		V	
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$			20		ns
Charge Time	t _a				10.4		
Discharge Time	t _b				9.6		
Reverse Recovery Charge	Q _{RR}				9.7		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L _S				2.49		nΗ
Drain Inductance, DPAK	L _D				0.0164		
Drain Inductance, IPAK	L _D	T _A = 25°C			1.88		
Gate Inductance	L _G				3.46		
Gate Resistance	R_{G}				1.1		Ω

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 2. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.

^{4.} Switching characteristics are independent of operating junction temperatures.

TYPICAL PERFORMANCE CURVES

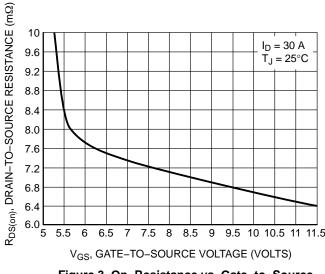
80



 $V_{DS} \ge 10 \text{ V}$ 70 DRAIN CURRENT (AMPS) 60 50 40 30 $T_J = 125^{\circ}C$ 20 $T_J = 25^{\circ}C$ ک 10 $T_J = -55^{\circ}C$ 0 2 3 5 V_{GS}, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



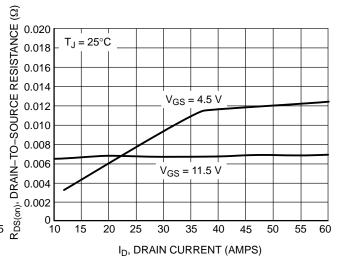
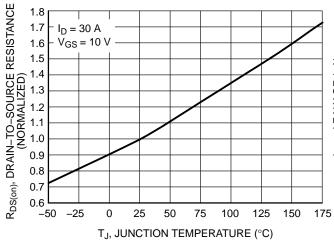


Figure 3. On–Resistance vs. Gate–to–Source Voltage

Figure 4. On–Resistance vs. Drain Current and Gate Voltage



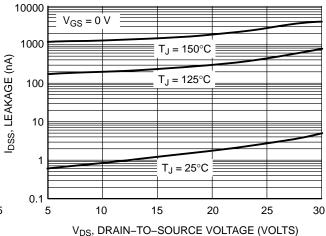
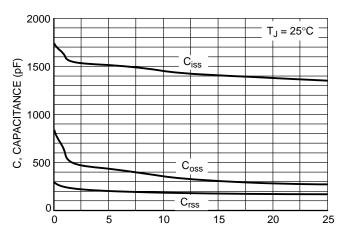


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Drain Voltage

TYPICAL PERFORMANCE CURVES



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

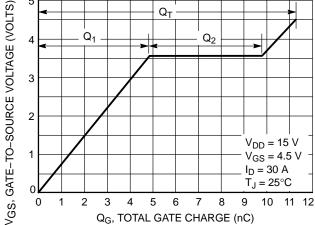


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge



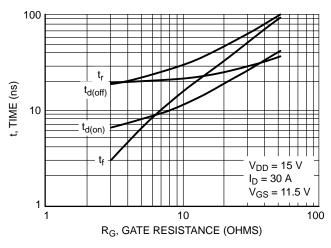


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

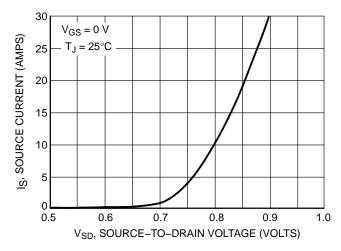


Figure 10. Diode Forward Voltage vs. Current

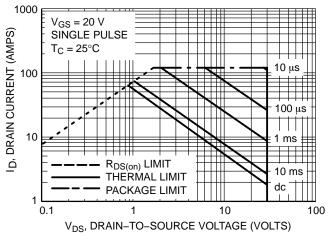


Figure 11. Maximum Rated Forward Biased Safe Operating Area

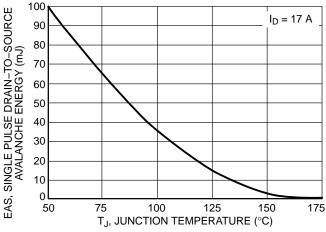


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL PERFORMANCE CURVES

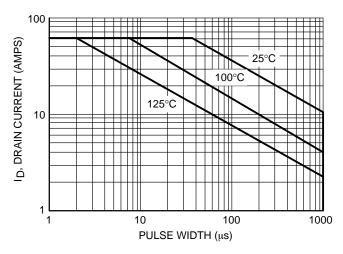


Figure 13. Avalanche Characteristics

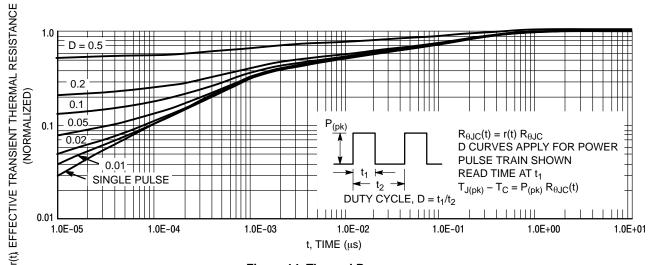


Figure 14. Thermal Response

ORDERING INFORMATION

Device	Package	Shipping [†]
NTD4808NT4G	DPAK (Pb-Free)	2500 / Tape & Reel
NTD4808N-1G	IPAK (Pb-Free)	75 Units / Rail
NVD4808NT4G*	DPAK (Pb-Free)	2500 / Tape & Reel

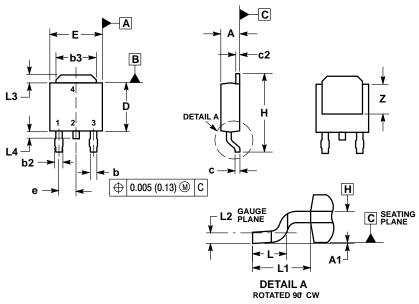
[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

^{*}NVD Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable.

PACKAGE DIMENSIONS

DPAK (SINGLE GUAGE)

CASE 369AA **ISSUE B**



- NOTES:

 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

 2. CONTROLLING DIMENSION: INCHES.

 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS b3, L3 and Z.

 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.

 5. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

 6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

$\overline{}$					
	INCHES		MILLIMETER		
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.030	0.045	0.76	1.14	
b3	0.180	0.215	4.57	5.46	
С	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
Е	0.250	0.265	6.35	6.73	
е	0.090	BSC	2.29 BSC		
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.108	REF	2.74 REF		
L2	0.020	BSC	0.51	BSC	
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
7	0.155		3 93		

SOLDERING FOOTPRINT*

6.20 3.00 0.244 0.118 2.58 0.102 5.80 1.60 6.17 0.228 0.063 0.243

 $\left(\frac{mm}{inches}\right)$ SCALE 3:1

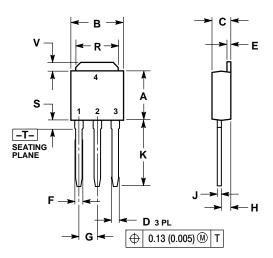
STYLE 2:

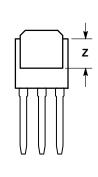
PIN 1. GATE 2. DRAIN 3. SOURCE 4. DRAIN

^{*}For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

IPAK CASE 369D ISSUE C





NOTES:

- DIMENSIONING AND TOLERANCING PER
 ANSI V14 FM 1082
- ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH.

	INCHES		MILLIM	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.35
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
Е	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.090 BSC		2.29	BSC
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.350	0.380	8.89	9.65
R	0.180	0.215	4.45	5.45
S	0.025	0.040	0.63	1.01
٧	0.035	0.050	0.89	1.27
Ζ	0.155		3.93	

STYLE 2:

- PIN 1. GATE 2. DRAIN
 - DRAIN
 SOURCE
 - 4. DRAIN

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